



# • Handheld XRF Comparison Matrix

Attribute	S1 TITAN	S1 SORTER	S1 TURBO <sup>SD</sup>	Tracer III-V <sup>+</sup>	Tracer III-SD	Tracer IV-SD	Tracer IV-GEO
<b>Customer Application</b>							
Application Specific	X	X	X				
Alloy Analysis Point-and-Shoot Capabilities	+++	++	+++				
Alloy Analysis Non-standard Alloys				++	+++	+++	+++
Routine Mining	+++		+++			+	+
Restricted Materials	+++		+++			+	+
University/Research Oriented				X	X	X	X
Art/Archeology				+++	+++	++	++
Research/Teaching				++	+++	++	++
Mining Research/Geochemistry	+++			+	++	++	+++
<b>Hardware Specifications</b>							
Detector	SDD or SiPIN	SiPIN	SDD	SiPIN	SDD	SDD	Large Area SDD
Typical Resolution	SDD = 147eV SiPIN = 195eV	215eV	145eV	195eV	145eV	145eV	150eV
Tube Target	Rh	Ag	Ag	Rh	Rh	Rh	Rh
Filter/Secondary Target	Automatic 5 Positions	Single Position	Automatic 5 Positions	Manual (4 provided). User can make their own.	Manual (4 provided). User can make their own.	User Selectable Automatic 5 Position	User Selectable Automatic 5 Position
<b>Accessories</b>							
Enclosed Benchtop Stand			X	X	X	X	X
Miniature Sample Table and Instrument Stand	X		X	X	X	X	X
Miniature Battery Operated Vacuum Pump				X	X	X	X
Data Analysis, Calibration, Spectral Sorting and Real-Time Viewing Software				X	X	X	X
Tripod with Articulating Mounting Arm				X	X	X	X
<b>Other Information</b>							
User Calibrations Allowed				X	X	X	X
User Control of X-ray Tube Voltage and Current				X	X	X	X
Laptop control of analyzer				X	X	X	X
Front panel control of analyzer	X	X	X	X	X	X	X
Price	SDD = \$\$ SiPIN = \$	\$	\$\$	\$\$\$	\$\$\$	\$\$\$	\$\$\$\$
Maximum Sample Temperature	SE / SP 500° C LE 150° C	500° C	SD 500° C LE 150° C	150° C	150° C	150° C	150° C

Note: Many features listed are optional - check with your salesperson for exact configuration and pricing

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